L Numbe	r Hits	Search Text	DB	Time stamp
1	3791	716/\$.ccls.	USPAT	2003/03/27 07:14
2	296	LSI same inspection	USPAT	2003/03/27 07:14
3	73		USPAT	
4	6		USPAT	2003/03/27 07:15
		probabilit\$3	USPAT	2003/03/27 07:22
5	12055		USPAT; US-PGPUB;	2003/03/27 07:24
-	4	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$.as.	EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/03/27 07:24
6	12024	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$4.as.	DERWENT; IBM_TDB USPAT; US-PGPUB;	2003/03/27 07:25
7	12016	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$4.as. and lsi and inspection	EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB;	2003/03/27 07:25
8	5	(ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and lsi and inspection	EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/03/27 07:28
9	42	(ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/03/27 07:28
10	37	((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and Isi and inspection)	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/03/27 07:28
11	433675	(((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and Isi and inspection)) and defect or failure	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/03/27 07:28
12	29	(((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and Isi and inspection)) and (defect or failure)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/03/27 07:47
_	548	((716/19) or (716/21)).CCLS.	IBM_TDB	0000100100100
_	435	((716/2),CCLS.	USPAT	2003/03/26 14:32
_	620	(716/4).CCLS.	USPAT	2003/03/26 14:32
_	985	inspect\$3 same pattern same (defect or failure)	USPAT	2003/03/26 14:33
-	1486	(((716/19) or (716/21)).CCLS.) ((716/2).CCLS.) ((716/4).CCLS.)	USPAT USPAT	2003/03/26 14:33 2003/03/26 14:33
-	18	((716/4).00Ld.) (inspect\$3 same pattern same (defect or failure)) and ((((716/19) or (716/21)).CCLS.) ((716/2).CCLS.) ((716/4).CCLS.))	USPAT	2003/03/26 15:48
-	4233	wafer near3 inspection	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/03/26 17:16
			IBM_TDB	

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-	754	(wafer near3 inspection) and particle and pattern	LICEAT	
	1	t was map assertly and particle and pattern	USPAT;	2003/03/26 17:17
			US-PGPUB:	1
			EPO; JPO;	
			DERWENT:	
-	24	(wafer near3 inspection) and particle and pattern and failure near3 probabilit\$3	IBM_TDB	
			USPAT:	2002/02/20 47.00
			1	2003/03/26 17:39
		•	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	1		IBM TDB	